제25회 한국반도체학술대회

 The 25<sup>th</sup> Korean Conference on Semiconductors

 2018년 2월 5일(월)-7일(수), 강원도 하이원리조트 컨벤션 호텔

## 2018년 2월 7일(수), 13:15-14:45 Room D (함백II+III, 5층)

## E. Compound Semiconductors 분과 [WD3-E] GaN Device

WD3-E-1 13:15-13:30	Enhancement of Gate Controllability and Suppression of Current Collapse in AlGaN/GaN HEMT Fabricated on GaN-Based Cantilever Quan Dai, Dong-Hyeok Son, Ryun-Hwi Kim, Jun-Hyeok Lee, Terirama Thingujam, Jung-Min Ju, and Jung-Hee Lee School of electronics engineering, Kyungpook National University
WD3-E-2 13:30-13:45	Improvement of Bias-Induced Vth Stability in Recessed-Gate AlGaN/GaN MIS-HEMTs with Nitrogen-Incorporated Al <sub>2</sub> O <sub>3</sub> Gate Insulator Myoung-Jin Kang <sup>1</sup> , Cheol-Hee Lee <sup>1</sup> , Su-Keun Eom <sup>1</sup> , Jae-Gil Lee <sup>1</sup> , Ho-Young Cha <sup>2</sup> , and Kwang-Seok Seo <sup>1</sup> <sup>1</sup> Department of Electrical and Computer Engineering and Inter-University Semiconductor Research Center, Seoul National University, <sup>2</sup> Department of Electronic and Electrical Engineering, Hongik University
WD3-E-3 13:45-14:00	Proton Irradiation Effects on AlGaN/GaN HEMT Isolated by Ion Implantation Dong-Seok Kim <sup>1</sup> , Sun Mog Yeo <sup>1</sup> , Jun-Hyeok Lee <sup>2</sup> , and Jung-Hee Lee <sup>2</sup> <sup>1</sup> Korea Multi-Purpose Accelerator Complex, KAERI, <sup>2</sup> School of Electronics Engineering, Kyungpook National University
WD3-E-4 14:00-14:15	Low Energy Proton Irradiation Effects in AlGaN/GaN-on-Si HEMTs Dongmin Keum, Geunho Cho, and Hyungtak Kim Department of Electronic and Electrical Engineering, Hongik University
WD3-E-5 14:15-14:30	The Characteristic of GaN Vertical Nanowire for Low Voltage Application Dong-Hyeok Son, Quan Dai, Ryun-Hwi Kim, Jun-Hyeok Lee, Hyun-Su Lee, and Jung-Hee Lee School of Electronics Engineering, Kyungpook National University
WD3-E-6 14:30-14:45	Development of 4-Inch AlGaN/GaN High Electron Mobility Transistors Grown on Semi-Insulating SiC Substrate with High Electron Mobility Chu-Young Cho, Yumin Koh, Hyeong-Ho Park, and Kyung-Ho Park <i>Electronic Devices Laboratory, KANC</i>